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Sheet 1 of 1 (use as many sheets as necessary)

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Filing Date 01/11/02
First Named Inventor Simpson et al.
Group Art Unit 1775
Examiner Name (not yet assigned)
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<sup>1</sup> Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the twoletter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. 6 Applicant is to place a check mark here if English language Translation is attached.